STP6NK50Z - STF6NK50Z STD6NK50Z

N-CHANNEL 500V - 0.93Ω - 5.6A TO-220/TO-220FP/DPAK Zener-Protected SuperMESH[™] MOSFET

TYPE	V_{DSS}	R _{DS(on)}	ID	Pw
STP6NK50Z	500 V	< 1.2 Ω	5.6 A	90 W
STF6NK50Z	500 V	< 1.2 Ω	5.6 A	25 W
STD6NK50Z	500 V	< 1.2 Ω	5.6 A	90 W

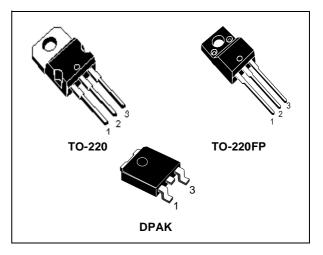
- TYPICAL $R_{DS}(on) = 0.93 \Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- GATE CHARGE MINIMIZED
- VERY LOW INTRINSIC CAPACITANCES
- VERY GOOD MANUFACTURING REPEATIBILITY

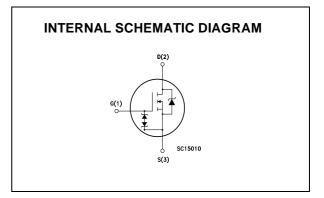


The SuperMESH[™] series is obtained through an extreme optimization of ST's well established stripbased PowerMESH[™] layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh[™] products.

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- IDEAL FOR OFF-LINE POWER SUPPLIES, ADAPTORS AND PFC
- LIGHTING





ORDER CODES

PART NUMBER	MARKING	PACKAGE	PACKAGING
STP6NK50Z	P6NK50Z	TO-220	TUBE
STF6NK50Z	F6NK50Z	TO-220FP	TUBE
STD6NK50ZT4	D6NK50Z	DPAK	TAPE & REEL

April 2004

STP6NK50Z - STF6NK50Z - STD6NK50Z

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Valu	Ie	Unit
		STP6NK50Z STD6NK50Z	STF6NK50Z	
V _{DS}	Drain-source Voltage ($V_{GS} = 0$)	500)	V
V _{DGR}	Drain-gate Voltage (R_{GS} = 20 k Ω)	500)	V
V_{GS}	Gate- source Voltage	± 3	0	V
I _D	Drain Current (continuous) at T _C = 25°C	5.6	5.6 (*)	Α
I _D	Drain Current (continuous) at T _C = 100°C	3.5	3.5 (*)	А
I _{DM} (•)	Drain Current (pulsed)	22.4	22.4 (*)	А
P _{TOT}	Total Dissipation at $T_C = 25^{\circ}C$	90	25	W
	Derating Factor	0.72	0.2	W/°C
V _{ESD(G-S)}	Gate source ESD(HBM-C=100pF, R=1.5KΩ)	300	0	V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5	5	V/ns
VISO	Insulation Withstand Voltage (DC)	-	2500	V
T _j T _{stg}	Operating Junction Temperature Storage Temperature	-55 to	150	°C

(•) Pulse width limited by safe operating area

(1) $I_{SD} \le 5.6A$, di/dt $\le 200 \text{ A}/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$.

(*) Limited only by maximum temperature allowed

THERMAL DATA

		TO-220 DPAK	TO-220FP	
Rthj-case	Thermal Resistance Junction-case Max	1.38	5	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5	5	°C/W
Τ _Ι	Maximum Lead Temperature For Soldering Purpose	300		°C

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T _j max)	5.6	A
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25 \text{ °C}, I_D = I_{AR}, V_{DD} = 50 \text{ V}$)	180	mJ

GATE-SOURCE ZENER DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
BV _{GSO}	Gate-Source Breakdown Voltage	Igs=± 1mA (Open Drain)	30			V

PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED) ON/OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	500			V
IDSS	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T _C = 125 °C			1 50	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±10	μA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 50 \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10V, I _D = 2.8 A		0.93	1.2	Ω

DYNAMIC

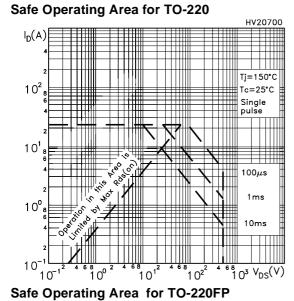
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	V _{DS} = 8 V, I _D = 2.8 A		4.3		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25V, f = 1 MHz, V _{GS} = 0		690 100 20		pF pF pF
C _{oss eq.} (3)	Equivalent Output Capacitance	$V_{GS} = 0V$, $V_{DS} = 0V$ to 400V		52		pF
t _{d(on)} tr td(off) t _f	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\label{eq:VDD} \begin{array}{l} V_{DD} = 250 \mbox{ V, } I_D = 2.8 \mbox{ A} \\ R_G = 4.7 \Omega \mbox{ V}_{GS} = 10 \mbox{ V} \\ (\mbox{Resistive Load see, Figure 3}) \end{array}$		12 23.5 31 23		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 400$ V, $I_D = 5.6$ A, $V_{GS} = 10$ V		24.6 4.9 13.3		nC nC nC

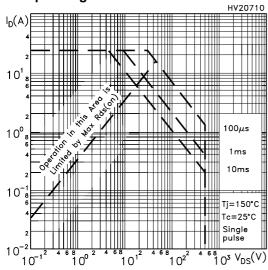
SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (2)	Source-drain Current Source-drain Current (pulsed)				5.6 22.4	A A
V _{SD} (1)	Forward On Voltage	$I_{SD} = 5.6 \text{ A}, \text{ V}_{GS} = 0$			1.6	V
t _{rr} Q _{rr} IRRM	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 5.6 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 48\text{V}, \text{ T}_{j} = 25^{\circ}\text{C}$ (see test circuit, Figure 5)		254 1.2 10		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 5.6 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 48\text{V}, T_j = 150^{\circ}\text{C}$ (see test circuit, Figure 5)		360 1.9 11		ns µC A

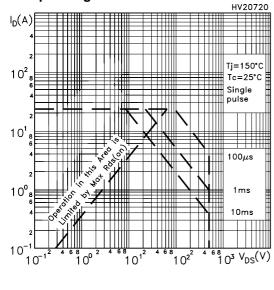
Note: 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
2. Pulse width limited by safe operating area.
3. C_{oss eq} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.



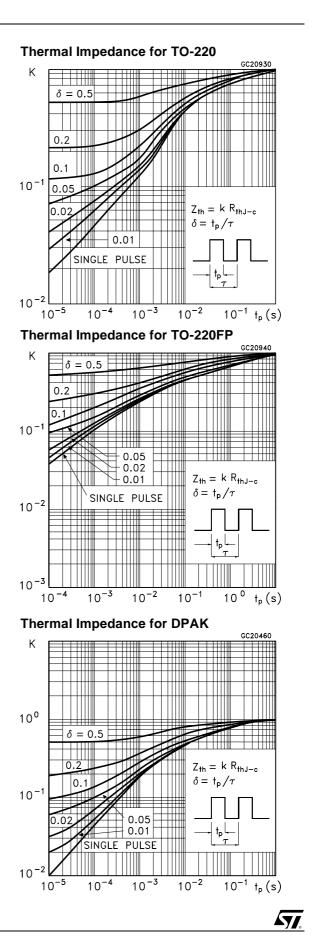




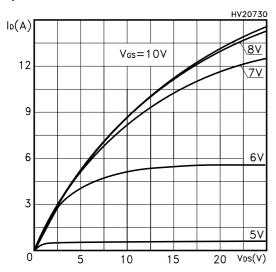
Safe Operating Area for DPAK



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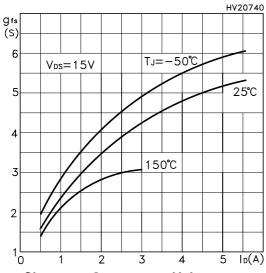


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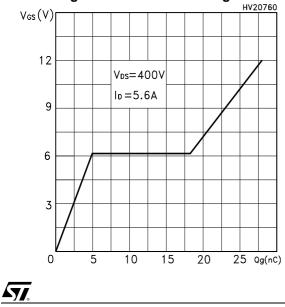


Output Characteristics

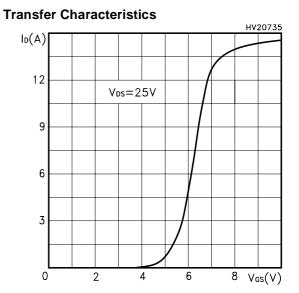
Transconductance



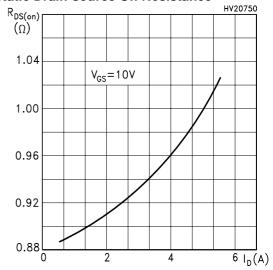


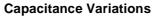


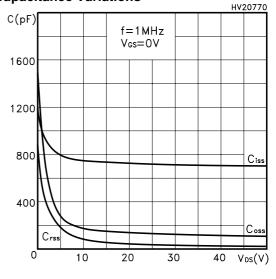
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Static Drain-source On Resistance

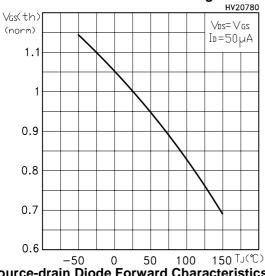




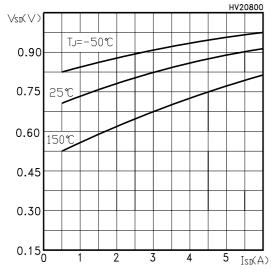


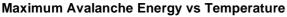
STP6NK50Z - STF6NK50Z - STD6NK50Z

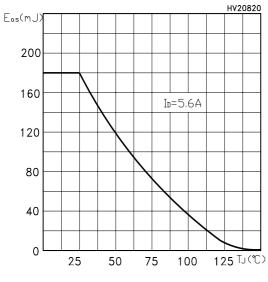
Normalized Gate Thereshold Voltage vs Temp.



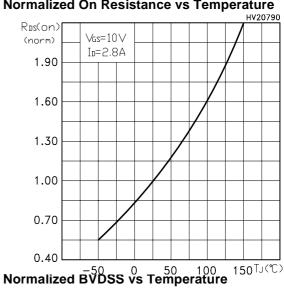
Source-drain Diode Forward Characteristics

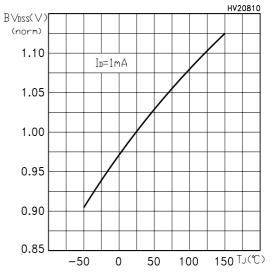




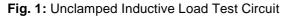








Normalized On Resistance vs Temperature



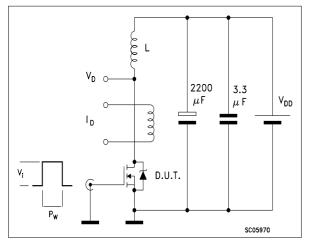


Fig. 3: Switching Times Test Circuit For Resistive Load

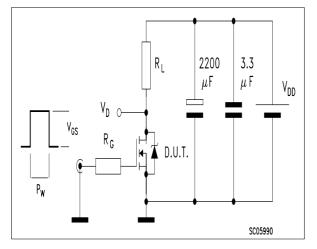
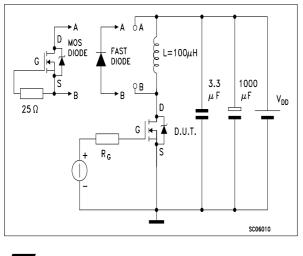


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times





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Fig. 2: Unclamped Inductive Waveform

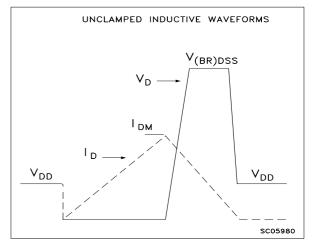
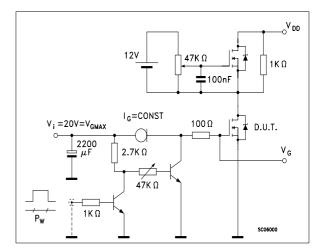
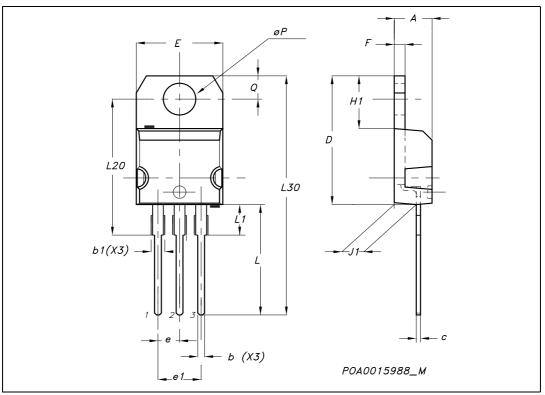


Fig. 4: Gate Charge test Circuit



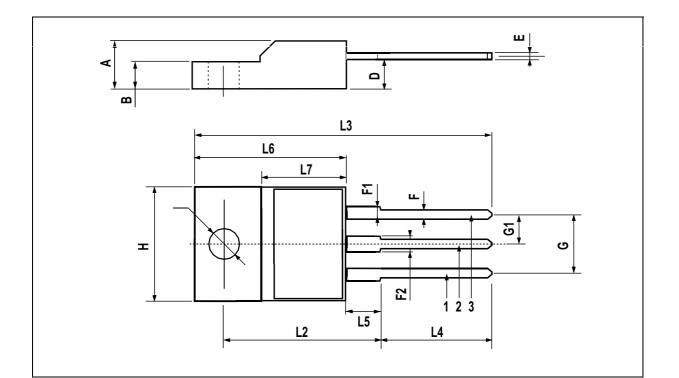
DIM	mm.					
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
Е	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116





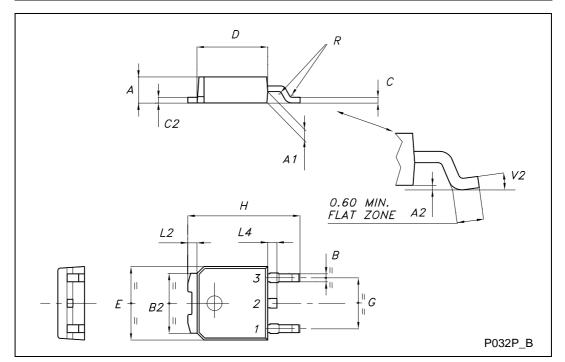
DIM.		mm.			inch	
DINI.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
Е	0.45		0.7	0.017		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.5	0.045		0.067
F2	1.15		1.5	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	.0385		0.417
L5	2.9		3.6	0.114		0.141
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126

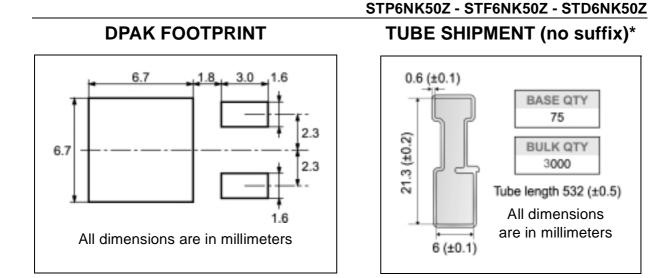
TO-220FP MECHANICAL DATA



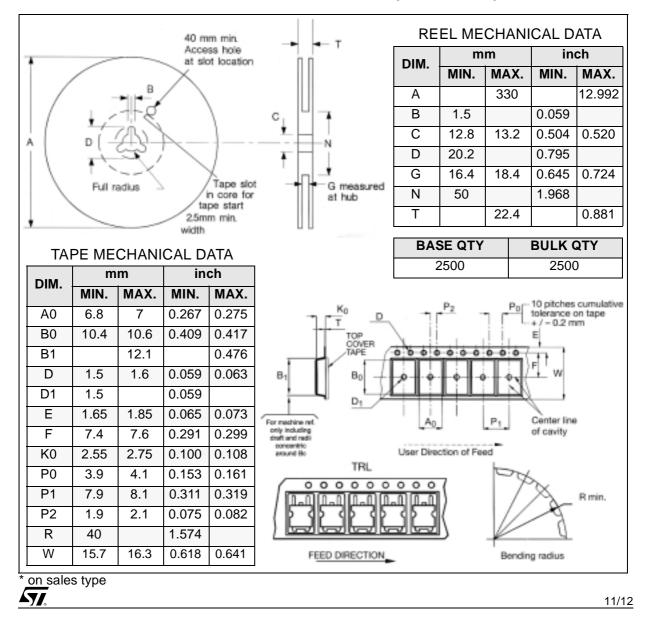
DIM.	mm			inch		
Dini.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
С	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
Н	9.35		10.10	0.368		0.398
L2		0.8			0.031	
L4	0.60		1.00	0.024		0.039

TO-252 (DPAK) MECHANICAL DATA





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